IEEE Citation Quick Reference

In-Text Citations

Max 6 authors: List all; 7+ use "et al."

In-Text Citations
Basic Format
Numbered citations in square brackets: [1], [2], [3]
Examples
Single citation: Recent research [1] has shown promising results.
Multiple citations (sequential): Several studies [1], [2], [5] support this approach.
Range of citations: Previous work [3]-[7] has explored this topic.
Multiple citations (range and individual): Various methods [1]-[3], [7], [10] have been proposed.
Author mention (optional in IEEE): Smith et al. [8] proposed a novel approach.
Same source cited again: Use the same number as first citation: [1]
Citation Numbering Rules
Order: - \square Number citations in order of first appearance in text - \square First citation = [1], second = [2], etc \square Same source cited again = use original number
Placement: - \square After punctuation (periods, commas) - \square Before colon if referencing upcoming material - \square No space between brackets and preceding word
Examples:
Correct: Recent studies show improvement [1], [2]. Wrong: Recent studies show improvement[1], [2].
Reference List Format
General Rules
 ☐ Title: "REFERENCES" (centered, uppercase) ☐ Numbering: [1], [2], [3] in order of citation ☐ Font: 8-point (for journal/conference papers) ☐ Hanging indent: 0.25 inch ☐ Single-space within entries ☐ Author names: First Initial(s). Last name
May 6 authors: List all: 7+ use "at al"

Common Source Formats

Journal Article

Standard format:

[1] A. Smith, B. Jones, and C. Lee, "Article title in sentence case," *IEEE Trans. Pattern Anal. Mach. Intell.*, vol. 42, no. 5, pp. 1234-1245, May 2020.

With DOI:

[2] M. Johnson, "Article title," *J. Comput. Sci.*, vol. 15, no. 3, pp. 456-470, Mar. 2023, doi: 10.1109/JCS.2023.1234567.

Early access:

[3] P. Davis, "Article title," *IEEE Trans. Neural Netw.*, early access, Jan. 15, 2024, doi: 10.1109/TNN.2024.7654321.

Conference Paper

Standard format:

[4] R. Brown and S. Garcia, "Paper title," in *Proc. IEEE Int. Conf. Comput. Vis. (ICCV)*, Oct. 2023, pp. 2345-2354.

With location:

[5] K. Williams, "Paper title," in *Proc. IEEE Conf. Comput. Vis. Pattern Recognit.* (CVPR), Seattle, WA, USA, Jun. 2023, pp. 1000-1008.

With DOI

[6] L. Martinez, "Paper title," in *Proc. Int. Conf. Mach. Learn. (ICML)*, 2023, pp. 5678-5687, doi: 10.1109/ICML.2023.123456.

Book

Complete book:

[7] J. Taylor, Book Title in Sentence Case, 3rd ed. New York, NY, USA: Wiley, 2022.

Book with editors:

[8] D. Wilson, Ed., Book Title, 2nd ed. Cambridge, MA, USA: MIT Press, 2021.

F-book

[9] A. Thompson, *Digital Book Title*. Boston, MA, USA: Pearson, 2023. [Online]. Available: https://www.publisher.com/ebook

Book Chapter

Standard format:

[10] E. Chen, "Chapter title," in *Book Title*, F. Davis, Ed. London, U.K.: Springer, 2023, ch. 5, pp. 89-112.

Multiple editors:

[11] G. Lee, "Chapter title," in *Book Title*, H. Kim and I. Park, Eds. Berlin, Germany: Springer, 2022, pp. 200-225.

Website/Online Source

With author and date:

[12] National Institute of Standards and Technology, "Page title," NIST, Gaithersburg, MD, USA, 2023. [Online]. Available: https://www.nist.gov/page

No author:

[13] "Page title," Website Name, 2024. [Online]. Available: https://www.example.com/page. Accessed: Jan. 15, 2024.

No date:

[14] J. Robinson, "Article title," Website Name. [Online]. Available: https://www.site.com/article. Accessed: Feb. 20, 2024.

Preprint (arXiv, etc.)

arXiv:

[15] K. Anderson and L. White, "Paper title," arXiv:2301.12345, 2023.

With version:

[16] M. Clark, "Paper title," arXiv:2302.67890v2, 2024.

Technical Report

Corporate/institutional:

[17] J. Miller et al., "Report title," Google Research, Mountain View, CA, USA, Tech. Rep. TR-2023-15, May 2023.

Government:

[18] "Report title," Nat. Inst. Standards Technol., Gaithersburg, MD, USA, NIST Tech. Rep. 8400, 2023.

Thesis/Dissertation

Ph.D. dissertation:

[19] S. Rodriguez, "Dissertation title here," Ph.D. dissertation, Dept. Comput. Sci., Stanford Univ., Stanford, CA, USA, 2022.

Master's thesis:

[20] T. Nguyen, "Thesis title," M.S. thesis, Dept. Elect. Eng., MIT, Cambridge, MA, USA, 2023.

Standard

IEEE standard:

[21] IEEE Standard for Software Testing, IEEE Std 829-2008, 2008, doi: 10.1109/IEEESTD.2008.4578383.

Other standards:

[22] Information Technology—Security Techniques, ISO/IEC 27001:2022, 2022.

Patent

U.S. patent:

[23] J. Smith, "Patent title," U.S. Patent 10 123 456, Nov. 5, 2023.

International patent:

[24] M. Brown, "Patent title," Patent WO 2023/123456 A1, Jun. 15, 2023.

Software/Code

GitHub repository:

[25] A. Developer, "Repository name," GitHub, 2023. [Online]. Available: https://github.com/user/repo

Software version:

[26] "MATLAB," ver. R2023a, MathWorks, Natick, MA, USA, 2023.

Dataset

With DOI:

[27] K. Researcher, "Dataset name," IEEE DataPort, 2023, doi: 10.21227/dataset.123.

Repository:

[28] L. Author, "Dataset title," Zenodo, 2023. [Online]. Available: https://doi.org/10.5281/zenodo.1234567

Common Abbreviations

Months

Jan., Feb., Mar., Apr., May, June, July, Aug., Sept., Oct., Nov., Dec.

Common Terms

- **vol.** = volume
- no. = number (issue)
- **pp.** = pages
- ed. = edition
- **Ed./Eds.** = Editor/Editors
- ch. = chapter
- **Proc.** = Proceedings
- Conf. = Conference
- Trans. = Transactions
- **J.** = Journal
- Mag. = Magazine
- Lett. = Letters
- Symp. = Symposium
- **Dept.** = Department
- Univ. = University
- Tech. Rep. = Technical Report
- Std. = Standard

Locations

- USA = United States (use for clarity)
- **U.K.** = United Kingdom
- State abbreviations: CA, NY, MA, TX, etc.

IEEE Journal Title Abbreviations

Common Abbreviations

IEEE Trans. *Pattern Anal. Mach. Intell.* (TPAMI) - *IEEE Trans. Neural Netw. Learn. Syst.* (TNNLS) - *IEEE Trans. Comput.* (TC) - *IEEE Trans. Signal Process.* (TSP) - *IEEE Trans. Wireless Commun.* (TWC) - *IEEE Trans. Power Electron.* (TPEL)

Other IEEE Publications: - *IEEE Commun. Mag. - IEEE Comput. Graphics Appl. - IEEE J. Sel. Areas Commun. - IEEE Access* (no abbreviation, full title)

Conference Proceedings: - Proc. IEEE Conf. Comput. Vis. Pattern Recognit. (CVPR) - Proc. IEEE Int. Conf. Comput. Vis. (ICCV) - Proc. Adv. Neural Inf. Process. Syst. (NeurIPS)

Check IEEE Reference Guide for complete list

Author Format

One Author

[1] A. Smith, "Title," ...

Two Authors

[2] A. Smith and B. Jones, "Title," ...

Three Authors

[3] A. Smith, B. Jones, and C. Lee, "Title," ...

Four to Six Authors

[4] A. Smith, B. Jones, C. Lee, and D. Brown, "Title," ...

Seven or More Authors

[5] A. Smith et al., "Title," ...

Note: List first 6 authors, then "et al."

Special Cases

No Author

Start with title, then organization or publication

[1] "Article title," Website Name, Year. [Online]. Available: URL

No Date

Use "n.d." or omit if not available

[2] J. Smith, "Article title," n.d. [Online]. Available: URL

Multiple Works by Same Author

Number in order of citation (not alphabetical)

- [3] J. Smith, "First cited paper," ...
- [8] J. Smith, "Second cited paper," ...

Forthcoming/In Press

[4] M. Jones, "Article title," IEEE Trans. Comput., to be published.

Unpublished/Submitted

Quick Comparison Table

Element	IEEE Format
In-text	[1], [2], [3]
Order	Sequence of citation
Authors	A. Smith and B. Jones
Max authors	6 (then et al.)
Title	Sentence case
Journal	Italics, abbreviated
Volume	vol. 42
Issue	no. 3
Pages	pp. 123-145
Date	Month Year
DOI	doi: 10.1109/XXX

Common Mistakes

Author-year format: (Smith, 2023) Numbered format: [1]
Alphabetical order Citation order (first mentioned = [1])
Full first names: John Smith Initials: J. Smith
Title Case for articles: "The Impact of Technology" Sentence case: "The impact of technology"
Full journal names: IEEE Transactions on Pattern Analysis and Machine Intelligence Abbreviated: IEEE Trans. Pattern Anal. Mach. Intell.
Missing comma before year: vol. 42 2023 Comma before year: vol. 42, no. 3, pp. 123-145, Mar. 2023
"Page" or "pages" spelled out Use pp. for page numbers
Ampersand (&) between authors "and" between authors: Smith and Jones

Quick Reference: Building a Citation

For a journal article, include in order:

- 1. [#] Reference number
- 2. Author initials and last name(s)3. "Article title in sentence case,"
- 4. Journal Name Abbreviated,
- 5. vol. X,
- 6. no. Y,
- 7. pp. XXX-YYY,
- 8. Month Year.

9. doi: (if available)

Example:

[1] A. Smith, B. Jones, and C. Lee, "Machine learning for network security," *IEEE Trans. Netw.*, vol. 28, no. 4, pp. 1234-1250, Aug. 2020, doi: 10.1109/TN.2020.123456.

In-Text Citation Context Examples

At end of sentence:

The method achieves 98% accuracy [1].

Multiple sources supporting claim:

Several approaches have been proposed [1]-[5], [8].

Specific claim from source:

According to [6], the algorithm runs in linear time.

Author mention (less common):

Smith et al. [7] demonstrated superior performance.

Comparing sources:

While [2] suggests one approach, [5] proposes an alternative.

Reference to figures/tables in cited work:

The results in [3, Fig. 2] show significant improvement.

Sample Reference List

REFERENCES

- [1] A. Smith and B. Jones, "Deep learning for intrusion detection," *IEEE Trans. Inf. Forensics Security*, vol. 15, pp. 1234-1250, 2020.
- [2] C. Lee, D. Brown, and E. Garcia, "Network security challenges," in *Proc. IEEE Symp. Security Privacy*, May 2021, pp. 456-470.
- [3] F. Wilson, *Cybersecurity Fundamentals*, 2nd ed. New York, NY, USA: Wiley, 2022.
- [4] G. Martinez, "Machine learning survey," arXiv:2301.12345, 2023.
- [5] National Institute of Standards and Technology, "Cybersecurity framework," NIST, Gaithersburg, MD, USA, 2023. [Online]. Available: https://www.nist.gov/framework

Tips for Success

Resources

Official IEEE Resources: - IEEE Reference Guide: ieee-dataport.org/documents/ieee-reference-guide - IEEE Author Center: ieeeauthorcenter.ieee.org - IEEE Editorial Style Manual: ieee.org/publications

Citation Tools: - IEEE citation format in reference managers (Zotero, Mendeley, EndNote) - Google Scholar: Set preferences to "IEEE" format - BibTeX: Use IEEEtran bibliography style

For complete IEEE citation guidelines, consult the IEEE Reference Guide and your target publication's author instructions.